


<b>Search Notes</b>  	<b>Application/Control No.</b>  10015613	<b>Applicant(s)/Patent Under Reexamination</b>  BAUDISCH, PATRICK
	<b>Examiner</b>  AARON M RICHER	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner
345	1.3-3.4 (text search only) - updated	5/10/08	AMR

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - updated - see search history	5/10/08	AMR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner